

CY14B101K

1-Mbit (128K x 8) nvSRAM With Real-Time Clock

Features

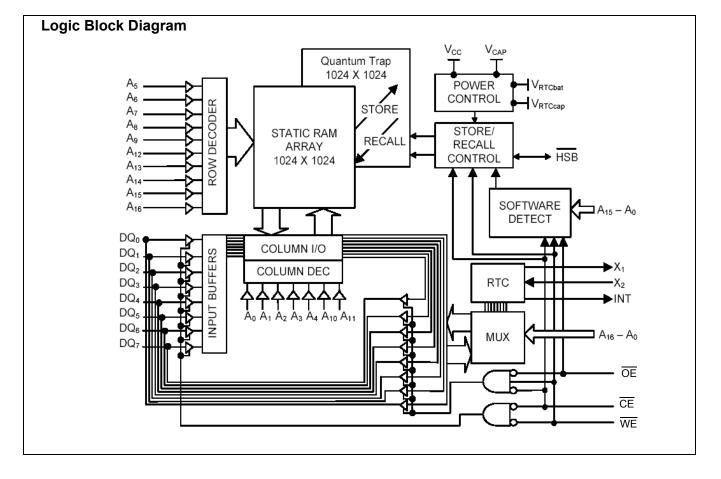
- Data Integrity of Cypress nvSRAM Combined with Full-Features Real-Time Clock
- Watchdog Timer
- Clock Alarm with programmable Interrupts
- Capacitor or battery backup for RTC
- 25 ns, 35 ns, and 45 ns Access Times
- "Hands-off" Automatic STORE on Power Down with only a small capacitor
- STORE to QuantumTrap™ Initiated by Software, device pin, or on Power Down
- RECALL to SRAM Initiated by Software or on Power Up
- Unlimited READ, WRITE and RECALL Cycles
- · High-reliability
 - Endurance to 1 Million Cycles
 - Data Retention: 100 years

- 5 mA Typical I_{CC} at 200-ns Cycle Time
- Single 3V Operation +20%, -10%
- SSOP Package (ROHS compliant)

Functional Description

The Cypress CY14B101K combines a 1-Mbit nonvolatile static RAM with a full-featured real-time clock in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap[™] technology producing the world's most reliable nonvolatile memory. The SRAM can be read and written an unlimited number of times, while independent, nonvolatile data resides in the nonvolatile elements.

The Real-Time Clock function provides an accurate clock with leap year tracking and a programmable, high accuracy oscillator. The Alarm function is programmable for one-time alarms or periodic seconds, minutes, hours, or days. There is also a programmable Watchdog Timer for process control.





Pin Configurations

V _{CAP}	1 ()		48	
A ₁₆	2		40 47	$\Box A_{15}$
A ₁₄	3		46	
A ₁₂	4		45	
A ₇	5		44	$\square A_{13}$
$A_6 \square$	6		43	$\square A_8$
A ₅	7		42	$\Box A_9$
	8		41	
A4 🗖	9	8-SSOP	40	$\square A_{11}$
NC	10 4	10-330P	39	
NC	11	Гор View	38	
NC 🗌	12		37	□ NC
V _{SS}	¹³ (no	ot to scale)	36	□ V _{SS}
	14		35	
V _{RTCbat}	15		34	□ V _{RTCcap}
DQ0	16		33	DQ6
Ag 🗖	17		32	
A ₂	18		31	□ A ₁₀
A ₁	19		30	
A0 🗆	20		29	DQ7
DQ1	21		28	DQ5
DQ2	22		27	DQ4
X ₁	23		26	DQ3
X ₂	24		25	□ V _{CC}
L				J

Pin Definitions

Pin Name	I/O Type	Description
A ₀ -A ₁₆	Input	Address Inputs used to select one of the 131,072 bytes of the nvSRAM.
DQ0 - DQ7	Input/Output	Bidirectional Data I/O lines. Used as input or output lines depending on operation
NC	No Connect	No Connects. This pin is not connected to the die
WE	Input	Write Enable Input, active LOW. When selected LOW, enables data on the I/O pins to be written to the address location latched by the falling edge of CE.
CE	Input	Chip Enable Input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
OE	Input	Output Enable, active LOW . The active low \overline{OE} input enables the data output buffers during read cycles. Deasserting \overline{OE} high causes the I/O pins to tri-state.
X ₁	Output	Crystal Connection, drives crystal on start-up.
X ₂	Input	Crystal Connection for 32.768-kHz crystal.
V _{RTCcap}	Power Supply	Capacitor-supplied backup RTC supply voltage. (Left unconnected if V _{RTCbat} is used)
V _{RTCbat}	Power Supply	Battery-supplied backup RTC supply voltage. (Left unconnected if V _{RTCcap} is used)
INT	Output	Interrupt Output . Can be programmed to respond to the clock alarm, the watchdog timer and the power monitor. Programmable to either active HIGH (push/pull) or LOW (open-drain)
V _{SS}	Ground	Ground for the device. Should be connected to ground of the system.
V _{CC}	Power Supply	Power Supply inputs to the device.
HSB	Input/Output	Hardware Store Busy . When LOW this output indicates a Hardware Store is in progress. When pulled low external to the chip it will initiate a nonvolatile STORE operation. A weak internal pull-up resistor keeps this pin HIGH if not connected. (Connection Optional)
V _{CAP}	Power Supply	Autostore [™] Capacitor. Supplies power to nvSRAM during power loss to store data from SRAM to nonvolatile elements.



Device Operation

The CY14B101K nvSRAM is made up of two functional components paired in the same physical cell. These are a SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM can be transferred to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to SRAM (the RECALL operation). This unique architecture allows all cells to be stored and recalled in parallel. During the STORE and RECALL operations SRAM READ and WRITE operations are inhibited. The CY14B101K supports unlimited reads and writes just like a typical SRAM. In addition, it provides unlimited RECALL operations from the nonvolatile cells and up to 1 million STORE operations.

SRAM Read

<u>The CY14B101K performs a READ cycle whenever CE and OE are low while WE and HSB are high. The address specified on pins A₀₋₁₆ determines which of the 131,072 data bytes will be accessed. When the READ is initiated by an address transition, the outputs will be valid after a delay of t_{AA} (READ cycle #1). If the READ is initiated by CE or OE, the outputs will be valid at t_{ACE} or at t_{DOE}, whichever is later (READ cycle #2). The data outputs will repeatedly respond to address changes within the t_{AA} access time without the need for transitions on any control input pins, and will remain valid until another address change or until CE or OE is brought high, or WE or HSB is brought low.</u>

SRAM Write

A W<u>RITE</u> cycle is performed whenever \overline{CE} and \overline{WE} are low and HSB is high. The address inputs must be stable prior to <u>entering the WRITE</u> cycle and must remain stable until either \overline{CE} or WE goes high at the end of the cycle. The data on the common I/O pins DQ₀₋₇ will <u>be</u> written into the memory if it is valid t_{SD} before the end of a WE controlled WRITE or before the end of an CE-controlled WRITE. It is recommended that \overline{OE} be kept high during the entire WRITE cycle to avoid data bus contention on common I/O lines. If \overline{OE} is left low, internal circuitry will turn off the output buffers t_{HZWE} after WE goes low.

AutoStore[™] Operation

The CY14B101K stores data to nvSRAM using one of three storage operations. <u>These</u> three operations are Hardware Store, activated by HSB, Software Store, activated by an address sequence, and AutoStore, on device power-down. AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B101K.

During normal operation, the device will draw current from V_{CC} to charge a capacitor connected to the V_{CAP} pin. This stored charge will be used by the chip to perform a single STORE operation. If the voltage on the V_{CC} pin drops below V_{SWITCH}, the part will automatically disconnect the V_{CAP} pin from V_{CC}. A STORE operation will be initiated with power provided by the V_{CAP} capacitor.

Figure 1 shows the proper connection of the storage capacitor (V_{CAP}) for automatic store operation. Refer to the DC Characteristics table for the size of V_{CAP}. The voltage on the V_{CAP} pin is driven to 5V by a charge pump internal to the chip. A pull-up should be placed on WE to hold it inactive during power-up.

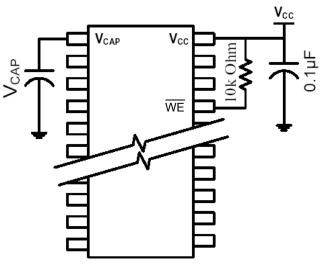


Figure 1. AutoStore[™] Mode

To reduce unnecessary nonvolatile stores, AutoStore and Hardware Store operations will be ignored unless at least one WRITE operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a WRITE operation has taken place. The HSB signal can be monitored by the system to detect an AutoStore cycle is in progress.

Hardware STORE (HSB) Operation

The CY14B101K provides the HSB pin for controlling and acknowledging the STORE operations. The HSB pin can be used to request a hardware STORE cycle. When the HSB pin is driven low, the CY14B101K will conditionally initiate a STORE operation after t_{DELAY} . An actual STORE cycle will only begin if a WRITE to the SRAM took place since the last STORE or RECALL cycle. The HSB pin also acts as an open drain driver that is internally driven low to indicate a busy condition while the STORE (initiated by any means) is in progress.

SRAM_READ and WRITE operations that are in progress when HSB is driven low by any means are given time to complete before the STORE operation is initiated. After HSB goes low, the CY14B101K will continue SRAM operations for t_{DELAY} . During t_{DELAY} , multiple SRAM READ operations may take place. If a WRITE is in progress when HSB is pulled low it will be allowed a time, t_{DELAY} , to complete. However, any SRAM WRITE cycles requested after HSB goes low will be inhibited until HSB returns high.

During any STORE operation, regardless of how it was initiated, the CY14B101K will continue to drive the HSB pin low, releasing it only when the STORE is complete. Upon completion of the STORE operation the CY14B101K will remain disabled until the HSB pin returns high.

If HSB is not used, it should be left unconnected.

Hardware RECALL (Power-Up)

During power-up, or after any low-power condition ($V_{CC} < V_{SWITCH}$), an internal RECALL request will be latched. When V_{CC} once again exceeds the sense voltage of V_{SWITCH} , a



RECALL cycle will automatically be initiated and will take $t_{\mbox{\scriptsize HRECALL}}$ to complete.

Software STORE

Data can be transferred from the SRAM to the nonvolatile memory by a software address sequence. The CY14B101K <u>software STORE</u> cycle is initiated by executing sequential CE-controlled READ cycles from six specific address locations in exact order. During the STORE cycle an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. Once a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of READs from specific addresses is used for STORE initiation, it is important that no other READ or WRITE accesses intervene in the sequence, or the sequence will be aborted and no STORE or RECALL will take place.

To initiate the software STORE cycle, the following READ sequence must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8FC0 Initiate STORE cycle

The software sequence may be clocked with CE-controlled READs or OE-controlled READs. Once the sixth address in the sequence has been entered, the STORE cycle will commence and the chip will be disabled. It is important that READ cycles and not WRITE cycles be used in the sequence, although it is not necessary that OE be low for the sequence to be valid. After the t_{STORE} cycle time has been fulfilled, the SRAM will again be activated for READ and WRITE operation.

Software RECALL

Data can be transferred from the nonvolatile memory to the SRAM by a software address sequence. A software RECALL cycle is initiated with a sequence of READ operations in a manner similar to the software STORE initiation. To initiate the RECALL cycle, the following sequence of CE-controlled READ operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4C63 Initiate RECALL cycle

Internally, RECALL is a two-step procedure. First, the SRAM data is cleared, and second, the nonvolatile information is transferred into the SRAM cells. After the t_{RECALL} cycle time the SRAM will once again be ready for READ and WRITE

operations.The RECALL operation in no way alters the data in the non-volatile elements.

Preventing AutoStore

The AutoStore function can be disabled by initiating an AutoStore Disable sequence. A sequence of read operations is performed in a manner similar to the software STORE initiation. To initiate the AutoStore Disable sequence, the following sequence of \overline{CE} -controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8B45 AutoStore Disable

The AutoStore can be re-enabled by initiating an AutoStore Enable sequence. A sequence of read operations is performed in a manner similar to the software RECALL initiation. To initiate <u>the</u> AutoStore Enable sequence, the following sequence of CE-controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4B46 AutoStore Enable

If the AutoStore function is disabled or re-enabled a manual STORE operation (Hardware or Software) needs to be issued to save the AutoStore state through subsequent power-down cycles. The part comes from the factory with AutoStore enabled.

Data Protection

The CY14B101K protects data from corruption during low-voltage conditions by inhibiting all externally initiated STORE and WRITE operations. The low voltage condition is detected when $V_{CC} \leq V_{SWITCH}$. If the CY14B101K is in a WRITE mode (both CE and WE low) at power-up, after a RECALL, or after a STORE, the WRITE will be inhibited until a negative transition on CE or WE is detected. This protects against inadvertent writes during power-up or brown-out conditions.

Noise Considerations

The CY14B101K is a high-speed memory and so must have a high-frequency bypass capacitor of approximately 0.1 μF connected between V_{CC} and V_{SS} , using leads and traces that are as short as possible. As with all high-speed CMOS ICs, careful routing of power, ground and signals will reduce circuit noise.



Table 1. Mode Selection

CE	WE	OE	A15 - A0	Mode	I/O	Power
Н	Х	Х	Х	Not Selected	Output High Z	Standby
L	Н	L	Х	Read SRAM	Output Data	Active
L	L	Х	Х	Write SRAM	Input Data	Active
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8B45	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Autostore Disable	Output Data Output Data Output Data Output Data Output Data Output Data Output Data	Active [1,2,3]
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4B46	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Autostore Enable	Output Data Output Data Output Data Output Data Output Data Output Data	Active [1,2,3]
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Store	Output Data Output Data Output Data Output Data Output Data Output High Z	Active I _{CC2} [1,2,3]
L	Н	L	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile Recall	Output Data Output Data Output Data Output Data Output Data Output High Z	Active [1,2,3]

Low Average Active Power

CMOS technology provides the CY14B101K, the benefit of drawing significantly less current when it is cycled at times longer than 50 ns. *Figure 2* shows the relationship between I_{CC} and READ/WRITE cycle time. Worst-case current consumption is shown for commercial temperature range, V_{CC} = 3.6V, and chip enable at maximum frequency. Only standby current is drawn when the chip is disabled. The overall average current drawn by the CY14B101K depends on the following items:

- 1. The duty cycle of chip enable.
- 2. The overall cycle rate for accesses.
- 3. The ratio of READs to WRITEs.
- 4. The operating temperature.
- 5. The V_{CC} level.
- 6. I/O loading.

Real-Time Clock Operation

nvTIME Operation

The CY14B101K offers internal registers that contain Clock, Alarm, Watchdog, Interrupt, and Control functions. Internal double buffering of the clock and the clock/timer information registers prevents accessing transitional internal clock data during a read or write operation. Double buffering also circumvents disrupting normal timing counts or clock accuracy of the internal clock while accessing clock data. Clock and Alarm Registers store data in BCD format.

Clock Operations

The clock registers maintain time up to 9,999 years in one-second increments. The user can set the time to any calendar time and the clock automatically keeps track of days of the week and month, leap years and century transitions. There are eight registers dedicated to the clock functions which are used to set time with a write cycle and to read time during a read cycle. These registers contain the Time of Day in BCD format. Bits defined as "0" are currently not used and are reserved for future use by Cypress.

Notes:

^{1.} The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.

^{2.} While there are 17 address lines on the CY14B101K, only the lower <u>16 lines</u> are used to control software modes.

^{3.} I/O state depends on the state of \overline{OE} . The I/O table shown assumes \overline{OE} Low.



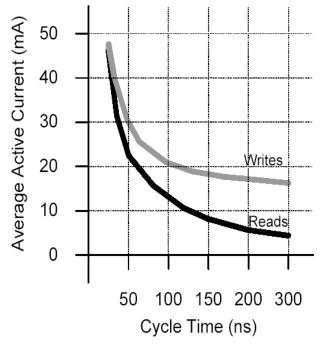


Figure 2. Current vs. Cycle Time

Reading the Clock

While the double-buffered RTC register structure reduces the chance of reading incorrect data from the clock, the user should halt internal updates to the CY14B101K clock registers before reading clock data to prevent the reading of data in transition. Stopping the internal register updates does not affect clock accuracy. The updating process is stopped by writing a "1" to the read bit "R" (in the flags register at 0x1FFF0), and will not restart until a "0" is written to the read bit. The RTC registers can then be read while the internal clock continues to run. Within 20 ms after a "0" is written to the read bit, all CY14B101K registers are simultaneously updated.

Setting the Clock

Setting the write bit "W" (in the flags register at 0x1FFF0) to a "1" halts updates to the CY14B101K registers. The correct day, date, and time can then be written into the registers in 24-hour BCD format. The time written is referred to as the "Base Time." This value is stored in nonvolatile registers and used in calculation of the current time. Resetting the write bit to "0" transfers those values to the actual clock counters, after which the clock resumes normal operation.

Backup Power

The RTC in the CY14B101K is intended for permanently powered operation. Either the V_{RTCcap} or V_{RTCbat} pin is connected depending on whether a capacitor or battery is chosen for the application. When primary power, V_{CC}, fails and drops below V_{SWITCH} the device will switch to the backup power supply.

The clock oscillator uses very little current, which maximizes the backup time available from the backup source. Regardless of clock operation with the primary source removed, the data stored in nvSRAM is secure, having been stored in the nonvolatile elements as power was lost.

During backup operation the CY14B101K consumes a maximum of 300 nanoamps at 2 volts. Capacitor or battery values should be chosen according to the application. Backup time values based on maximum current specs are shown below. Nominal times are approximately three times longer.

Table 2. RTC Backup Time

Capacitor Value	Backup Time
0.1F	72 hours
0.47F	14 days
1.0F	30 days

Using a capacitor has the obvious advantage of recharging the backup source each time the system is powered up. If a battery is used, a 3V lithium is recommended and the CY14B101K will only source current from the battery when the primary power is removed. The battery will not, however, be recharged at any time by the CY14B101K. The battery capacity should be chosen for total anticipated cumulative down-time required over the life of the system.

Stopping and Starting the Oscillator

The OSCEN bit in calibration register at 0x1FFF8 controls the starting and stopping of the oscillator. This bit is nonvolatile and shipped to customers in the "enabled" (set to 0) state. To preserve battery life while system is in storage OSCEN should be set to a 1. This will turn off the oscillator circuit extending the battery life. If the OSCEN bit goes from disabled to enabled, it will take approximately 5 seconds (10 seconds max) for the oscillator to start.

The CY14B101K has the ability to detect oscillator failure. This is recorded in the OSCF (Oscillator Failed bit) of the flags register at address 0x1FFF0. When the device is powered on (V_{CC} goes above V_{SWITCH}) the OSCEN bit is checked for "enabled" status. If the OSCEN bit is enabled and the oscillator is not active, the OSCF bit is set. The user should check for this condition and then write a 0 to clear the flag. It should be noted that in addition to setting the OSCF flag bit, the time registers are reset to the "Base Time" (see the section "Setting the Clock"), which is the value last written to the timekeeping registers. The Control/Calibration register and the OSCEN bit are not affected by the oscillator failed condition.

If the voltage on the backup supply (either V_{RTCcap} or V_{RTCbat}) falls below their respective minimum level the oscillator may fail, leading to the oscillator failed condition which can be detected when system power is restored.

The value of OSCF should be reset to 0 when the time registers are written for the first time. This will initialize the state of this bit which may have become set when the system was first powered on.

Calibrating the Clock

The RTC is driven by a quartz-controlled oscillator with a nominal frequency of 32.768 kHz. Clock accuracy will depend on the quality of the crystal, usually specified to 35 ppm limits at 25°C. This error could equate to +1.53 minutes per month. The CY14B101K employs a calibration circuit that can improve the accuracy to +1/–2 ppm at 25°C. The calibration circuit adds or subtracts counts from the oscillator divider circuit.



The number of times pulses are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in calibration register at 0x1FFF8. Adding counts speeds the clock up; subtracting counts slows the clock down. The Calibration bits occupy the five lower-order bits in the control register 8. These bits can be set to represent any value between 0 and 31 in binary form. Bit D5 is a Sign bit, where a "1" indicates positive calibration and a "0" indicates negative calibration. Calibration occurs within a 64 minute cycle. The first 62 minutes in the cycle may, once per minute, have one second either shortened by 128 or lengthened by 256 oscillator cycles.

If a binary "1" is loaded into the register, only the first 2 minutes of the 64 minute cycle will be modified; if a binary 6 is loaded, the first 12 will be affected, and so on. Therefore each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125,829,120 actual oscillator cycles. That is 4.068 or -2.034 ppm of adjustment per calibration step in the calibration register.

In order to determine how to set the calibration one may set the CAL bit in the flags register at 0x1FFF0 to 1, which causes the INT pin to toggle at a nominal 512 Hz. Any deviation measured from the 512 Hz will indicate the degree and direction of the required correction. For example, a reading of 512.010124 Hz would indicate a +20 ppm error, requiring a -10 (001010) to be loaded into the Calibration register. Note that setting or changing the calibration register does not affect the frequency test output frequency.

Alarm

The alarm function compares user-programmed values to the corresponding time-of-day values. When a match occurs, the alarm event occurs. The alarm drives an internal flag, AF, and may drive the INT pin if desired.

There are four alarm match fields. They are date, hours, minutes and seconds. Each of these fields also has a Match bit that is used to determine if the field is used in the alarm match logic. Setting the Match bit to "0" indicates that the corresponding field will be used in the match process.

Depending on the Match bits, the alarm can occur as specifically as one particular second on one day of the month, or as frequently as once per second continuously. The MSB of each alarm register is a Match bit. Selecting none of the Match bits (all 1s) indicates that no match is required. The alarm occurs every second. Setting the match select bit for seconds to "0" causes the logic to match the seconds alarm value to the current time of day. Since a match will occur for only one value per minute, the alarm occurs once per minute. Likewise, setting the seconds and minutes Match bits causes an exact match of these values. Thus, an alarm will occur once per hour. Setting seconds, minutes and hours causes a match once per day. Lastly, selecting all match values causes an exact time and date match. Selecting other bit combinations will not produce meaningful results; however the alarm circuit should follow the functions described.

There are two ways a user can detect an alarm event, by reading the AF flag or monitoring the INT pin. The AF flag in the flags register at 0x1FFF0 will indicate that a date/time match has occurred. The AF bit will be set to 1 when a match occurs. Reading the Flags/Control register clears the alarm

flag bit (and all others). A hardware interrupt pin may also be used to detect an alarm event.

Watchdog Timer

The watchdog timer is a free running down counter that uses the 32-Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator must be running for the watchdog to function. It begins counting down from the value loaded in the Watchdog Timer register.

The counter consists of a loadable register and a free-running counter. On power-up, the watchdog time-out value in register 0x1FFF7 is loaded into the counter load register. Counting begins on power-up and restarts from the loadable value any time the Watchdog Strobe (WDS) bit is set to 1. The counter is compared to the terminal value of 0. If the counter reaches this value, it causes an internal flag and an optional interrupt output. The user can prevent the time-out interrupt by setting WDS bit to 1 prior to the counter reaching 0. This causes the counter to be reloaded with the watchdog time-out value and to be restarted. As long as the user sets the WDS bit prior to the counter reaching the terminal value, the interrupt and flag never occurs.

New time-out values can be written by setting the watchdog write bit to 0. When the WDW is 0 (from the previous operation), new writes to the watchdog timeout value bits D5–D0 allow the time-out value to be modified. When WDW is a 1, then writes to bits D5–D0 will be ignored. The WDW function allows a user to set the WDS bit without concern that the watchdog timer value will be modified. A logical diagram of the watchdog time-out value to 0 would be otherwise meaningless and therefore disables the watchdog function.

The output of the watchdog timer is a flag bit WDF that is set if the watchdog is allowed to time-out. The flag is set upon a watchdog time-out and cleared when the Flags/Control register is read by the user. The user can also enable an optional interrupt source to drive the INT pin if the watchdog time-out occurs.

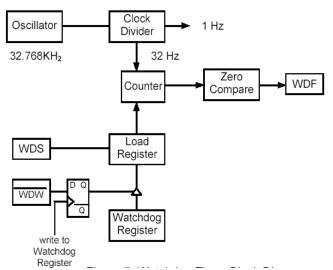


Figure 3. Watchdog Timer Block Diagram



Power Monitor

The CY14B101K provides a power management scheme with power-fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low-V_{CC} access. The power monitor is based on an internal band-gap reference circuit that compares the V_{CC} voltage to various thresholds.

As described in the AutoStore section previously, when V_{SWITCH} is reached as V_{CC} decays from power loss, a data store operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from V_{CC} to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source no data may be read or written and the clock functions are not available to the user. The clock continues to operate in the background. Updated clock data is available to the user after $t_{HRECALL}$ delay (See AutoStore/Power-up Recall) after V_{CC} has been restored to the device.

Interrupts

The CY14B101K provides three potential interrupt sources. They include the watchdog timer, the power monitor, and the clock/calendar alarm. Each can be individually enabled and assigned to drive the INT pin. In addition, each has an associated flag bit that the host processor can use to determine the cause of the interrupt. Some of the sources have additional control bits that determine functional behavior. In addition, the pin driver has three bits that specify its behavior when an interrupt occurs.

The three interrupts each have a source and an enable. Both the source and the enable must be active (true high) in order to generate an interrupt output. Only one source is necessary to drive the pin. The user can identify the source by reading the Flags/Control register, which contains the flags associated with each source. All flags are cleared to 0 when the register is read. The cycle must be a complete read cycle (WE high); otherwise the flags will not be cleared. The power monitor has two programmable settings that are explained in the power monitor section.

Once an interrupt source is active, the pin driver determines the behavior of the output. It has two programmable settings as shown below. Pin driver control bits are located in the Interrupts register. According to the programming selections, the pin can be driven in the backup mode for an alarm interrupt. In addition, the pin can be an active LOW (open-drain) or an active HIGH (push-pull) driver. If programmed for operation during backup mode, it can only be active LOW. Lastly, the pin can provide a one-shot function so that the active condition is a pulse or a level condition. In one-shot mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In level mode, the pin goes to its active polarity until the Flags/Control register is read by the user. This mode is intended to be used as an interrupt to a host microcontroller. The control bits are summarized as follows:

Watchdog Interrupt Enable - WIE. When set to 1, the watchdog timer drives the INT pin as well as an internal flag when a watchdog time-out occurs. When WIE is set to 0, the watchdog timer affects only the internal flag.

Alarm Interrupt Enable - AIE. When set to 1, the alarm match drives the INT pin as well as an internal flag. When set to 0, the alarm match only affects to internal flag.

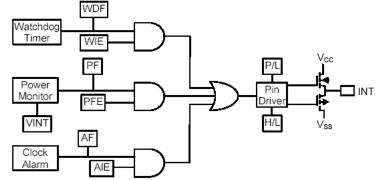
Power Fail Interrupt Enable - PFE. When set to 1, the power fail monitor drives the pin as well as an internal flag. When set to 0, the power fail monitor affects only the internal flag.

High/Low - H/L. When set to a 1, the INT pin is active high and the driver mode is push-pull. The INT pin can drive high only when $V_{CC} > V_{SWITCH}$. When set to a 0, the INT pin is active LOW and the drive mode is opendrain. Active LOW (open drain) is operational even in battery backup mode.

Pulse/Level - P/L. When set to a 1 and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a 0, the INT pin is driven high or low (determined by H/L) until the Flags/Control register is read.

When an enabled interrupt source activates the INT pin, an external host can read the Flags/Control register to determine the cause. Remember that all flags will be cleared when the register is read. If the INT pin is programmed for Level mode, then the condition will clear and the INT pin will return to its inactive state. If the pin is programmed for Pulse mode, then reading the flag also will clear the flag and the pin. The pulse will not complete its specified duration if the Flags/Control register is read. If the INT pin is used as a host reset, then the Flags/Control register should not be read during a reset.

During a power-on reset with no battery, the interrupt register is automatically loaded with the value 24h. This causes power-fail interrupt to be enabled with an active-LOW pulse.



WDF - Watchdog Timer Flag WIE - Watchdog Interrupt Enable PF - Power fail Flag PFE - Power Fail Enable AF - Alarm Flag AIE - Alarm Interrupt Enable P/L - Pulse Level H/L - High/Low

Figure 4. Interrupt Block Diagram



Table 3. RTC Register Map

				BCD	CD Format Data						
Register	D7	D6	D5	D4	D3	D2	D1	D0	Function/Range		
0x1FFFF		10s	Years			Y	ears		Years: 00–99		
0x1FFFE	0	0	0	10s Months	Months			Months: 01–12			
0x1FFFD	0	0	10s Day	of Month		Day (Of Month		Day of Month: 01–31		
0x1FFFC	0	0	0	0	0		Day of w	eek	Day of week: 01–07		
0x1FFFB	0	0	10s ⊢	lours		H	ours		Hours: 00–23		
0x1FFFA	0	1	0s Minute	S	Minutes				Minutes: 00–59		
0x1FFF9		1	0s Second	ds		Se	conds		Seconds: 00–59		
0x1FFF8	OSCEN	0	Cal Sign			Calibrati	on		Calibration Values ^[4]		
0x1FFF7	WDS	WDW		WDT Wat			Watchdog ^[4]				
0x1FFF6	WIE	AIE	PFE	ABE	H/L	P/L	0	0	Interrupts ^[4]		
0x1FFF5	M	0	10s Alar	m Date		Alar	m Day		Alarm, Day of Month: 01–31		
0x1FFF4	M	0	10s Aları	m Hours		Alarr	n Hours		Alarm, Hours: 00–23		
0x1FFF3	M	10 /	Alarm Min	utes	Alarm Minutes			Alarm, Minutes: 00–59			
0x1FFF2	M	10 /	Alarm Min	utes	Alarm, Seconds			Alarm, Seconds: 00–59			
0x1FFF1		10s Ce	enturies	Centur			nturies	Centuries: 00–99			
0x1FFF0	WDF	AF	PF	OSCF	0	CAL	W	R	Flags ^[4]		

Note: 4. Is a binary value, not a BCD value.



Table 4. Register Map Detail

				Time Keepi	ng - Years					
	D7	D6	D5	D4	D3	D2	D1	D0		
		10s	Years			Y	<i>ears</i>			
0x1FFFF		Contains the lower two BCD digits of the year. Lower nibble contains the value for years; upper nibble contains the value for 10s of years. Each nibble operates from 0 to 9. The range for the register is 0–99.								
		-		Time Keepin	g - Months	-				
	D7	D6	D5	D4	D3	D2	D1	D0		
	0	0	0	10s Month		M	onths			
0x1FFFE				er nibble contai ates from 0 to 1				; upper nibbl		
				Time Keepi	ing - Date					
	D7	D6	D5	D4	D3	D2	D1	D0		
	0	0	10s Day	of Month		Day	of Month			
0x1FFFD	upper nibble			month. Lower roperates from 0						
				Time Keep	ing - Day					
	D7	D6	D5	D4	D3	D2	D1	D0		
	0	0	0	0	0		Day of Week			
0x1FFFC	Lower nibble contains a value that correlates to day of the week. Day of the week is a ring counter that counts from 1 to 7 then returns to 1. The user must assign meaning to the day value, as the day is not integrated with the date									
	Time Keeping - Hours									
	D7	D6	D5	D4	D3	D2	D1	D0		
	12/24	0	10s H	lours		Н	ours			
0x1FFFB	Contains the BCD value of hours in 24 hour format. Lower nibble contains the lower digit and operates from 0 to 9 upper nibble (two bits) contains the upper digit and operates from 0 to 2. The range for the register is 0–23.									
	Time Keeping - Minutes									
	D7	D6	D5	D4	D3	D2	D1	D0		
	0		10s Minutes		Minutes					
0x1FFFA	Contains the BCD value of minutes. Lower nibble contains the lower digit and operates from 0 to 9; upper nibble contains the upper minutes digit and operates from 0 to 5. The range for the register is 0–59.									
				Time Keeping	g - Seconds					
	D7	D6	D5	D4	D3	D2	D1	D0		
	0		10s Seconds			Se	conds			
0x1FFF9				r nibble contain 0 to 5. The ran				; upper nibbl		
				Calibration	n/Control					
	D7	D6	D5	D4	D3	D2	D1	D0		
0X1FFF8	OSCEN	0	Calibration Sign			Calibration				
OSCEN	saves battery	/capacitor pov	ver during stora	ator is halted. W ige. On a no-ba	ttery power-u	ıp, this bit is s	et to 0.			
Calibration Sign	Determines i	f the calibration	n adjustment is	applied as an a	addition to or	as a subtracti	on from the tim	e-base.		
Calibration	These five bi	ts control the c	alibration of the	e clock.						



Table 4. Register Map Detail (continued)

				WatchDo	g Timer				
	D7	D6	D5	D4	D3	D2	D1	D0	
0x1FFF7	WDS	WDW			WE	DT	I	1	
WDS				ads and restarts /atchdog timer is					
WDW	written. This bits 5–0 to be	allows the user e written on the	to strobe the w next write to the	1 masks the wa vatchdog withou he Watchdog re nplete. This fund	t disturbing th gister. The ne	e time-out valu w value will be	ue. Setting this e loaded on th	s bit to 0 allow e next interna	
WDT	a multiplier o the maximun	Watchdog time-out selection. The watchdog timer interval is selected by the 6-bit value in this register. It represen a multiplier of the 32-Hz count (31.25 ms). The minimum range or time-out value is 31.25 ms (a setting of 1) an the maximum time-out is 2 seconds (setting of 3Fh). Setting the watchdog timer register to 0 disables the timer. These bits can be written only if the WDW bit was cleared to 0 on a previous cycle.							
				Interrupt Sta	tus/Control				
	D7	D6	D5	D4	D3	D2	D1	D0	
0x1FFF6	WIE	AIE	PFIE	ABE	H/L	P/L	0	0	
WIE	Watchdog In as well as the	terrupt Enable. e WDF flag. W	When set to 1 hen set to 0, th	and a watchdog	g time-out occ e-out affects o	urs, the watch only the WDF	ndog timer driv flag.	es the INT pi	
AIE		ipt Enable. Wh atch only affect		e alarm match d	rives the INT	pin as well as	the AF flag. V	Vhen set to 0	
PFIE		nable. When sonitor affects o		rm match drives	the INT pin a	as well as the	AF flag. Wher	n set to 0, the	
ABE	Alarm Batter backup mode	y-backup Enab e. When set to	le. When set to 0, the alarm w	o 1, the alarm int ill occur only wh	errupt (as cor ien V _{CC} > V _{S\}	itrolled by AIE ₩ITCH·) will function	even in batte	
H/L	High/Low. W	hen set to a 1,	the INT pin is a	driven active hig	h. When set t	o 0, the INT p	in is open dra	in, active LO	
P/L				is driven active is driven to an a					
	Alarm - Day								
	D7	D6	D5	D4	D3	D2	D1	D0	
	M	0	10s Ala	irm Date		Aları	n Date		
0x1FFF5	Contains the	alarm value fo	or the date of th	e month and th	e mask bit to	select or dese	lect the date	/alue.	
M		ng this bit to 0 o to ignore the o		e value to be us	ed in the aları	m match. Sett	ing this bit to ⁻	1 causes the	
				Alarm -	Hours		-		
	D7	D6	D5	D4	D3	D2	D1	D0	
	M	0	10s Alaı	rm Hours		Alarn	n Hours		
0x1FFF4	Contains the	alarm value fo	or the hours and	d the mask bit to	o select or des	select the hou	rs value.		
M		ng this bit to 0 o to ignore the h		irs value to be u	sed in the ala	rm match. Se	tting this bit to	1 causes the	
				Alarm - N	/linutes				
	D7	D6	D5	D4	D3	D2	D1	D0	
	M	0	10s Alarr	n Minutes		Alarm	Minutes		
0x1FFF3				and the mask bi					
Μ		ng this bit to 0 c to ignore the r		utes value to be	used in the al	arm match. S	etting this bit t	o 1 causes th	



Table 4. Register Map Detail (continued)

		Alarm - Seconds							
	D7	D6	D5	D4	D3	D2	D0		
	М	0	10s Alarr	n Seconds		Alarm	Seconds		
0x1FFF2	Contains the	alarm value fo	or the seconds	and the mask b	it to select or	deselect the se	econds' value		
M		Match. Setting this bit to 0 causes the seconds' value to be used in the alarm match. Setting this bit to 1 causes the match circuit to ignore the seconds value.							
				Time Keeping	g - Centuries				
	D7	D6	D5	D4	D3	D2	D1	D0	
0x1FFF1	0	0	10s C	enturies		Cen	turies		
				Fla	gs				
	D7	D6	D5	D4	D3	D2	D1	D0	
0x1FFF0	WDF	AF	PF	OSCF	0	CAL	W	R	
WDF				s set to 1 when he Flags/Contro			ed to reach 0 v	without being	
AF				hen the time and Flags/Control re			ed in the alarm	n registers with	
PF		ag. This read-c e Flags/Contro		1 when power f ad.	alls below the	e power-fail thre	eshold V _{SWITC}	_{CH} . It is cleared	
OSCF	This indicate		nts are no long	only if the oscilla jer valid. The us wer cycles.					
CAL				square wave is isabled) on pow		INT pin. When	set to 0, the IN	IT pin resumes	
W		Write Time. Setting the W bit to 1 freeze updates of the timekeeping registers. The user can then write them with updated values. Setting the W bit to 0 causes the contents of the time registers to be transferred to the timekeeping counters.							
R	register. The	user can then	read them with	a static image of hout concerns c capture, so the	ver changing	values causing	g system erro	rs. The R bit	





CY14B101K

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied55°C to +125°C
Supply Voltage on V_{CC} Relative to GND –0.5V to 4.1V
Voltage Applied to Outputs in High-Z State0.5V to V_{CC} + 0.5V
Input Voltage0.5V to Vcc+0.5V
Transient Voltage (<20 ns) on Any Pin to Ground Potential–2.0V to V_{CC} + 2.0V

Package Power Dissipation Capability (T _A = 25°C)	1.0W
Surface Mount Lead Soldering Temperature (3 Seconds)	+240°C
Output Short Circuit Current ^[5]	15 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	> 2001V
Latch-up Current	> 200 mA

Table 5. Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0°C to +70°C	2.7V to 3.6V
Industrial	–40°C to +85°C	2.7V to 3.6V

Shaded area contains Advance Information

Parameter	Description	Test Conditions	Min.	Max.	Unit	
I _{CC1}	Average V _{CC} Current	t_{RC} = 25 ns t_{RC} = 35 ns t_{RC} = 45 ns	Commercial		65 55 50	mA mA mA
		Dependent on output loading and cycle rate. Values obtained without output loads. I _{OUT} = 0mA.	Industrial		70 60 55	mA mA mA
I _{CC2}	Average V _{CC} Current during STORE	All Inputs Don't Care, V _{CC} = Max. Average current for duration t _{STORE}		3	mA	
I _{CC3}	Average V _{CC} Current at t _{AVAV} = 200 ns, 3V, 25°C typical	WE > (V _{CC} – 0.2). All other inputs cycling. Dependent on output loading and cycle rate. Value without output loads.		5	mA	
I _{CC4}	Average V _{CAP} Current during AutoStore Cycle	All Inputs Don't Care, V _{CC} = Max. Average current for duration t _{STORE}		3	mA	
I _{SB}	V _{CC} Standby Current	$\overline{\text{WE}}$ > (V _{CC} – 0.2). All others V _{IN} < 0.2V or > (V _{CC} Standby current level after nonvolatile cycle is con Inputs are static. f = 0MHz		2	mA	
I _{IX}	Input Leakage Current	V _{CC} = Max., V _{SS} ≤ V _{IN} ≤ V _{CC}		-1	+1	μΑ
I _{OZ}	Off-State Output Leakage Current	$\frac{V_{CC}}{CE} = \frac{Max., V_{SS} \le V_{IN} \le V_{CC},}{CE \text{ or } OE > V_{IH}}$		-1	+1	μA
V _{IH}	Input HIGH Voltage			2.2	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage			$V_{SS} - 0.5$	0.8	V
V _{OH}	Output HIGH Voltage	I _{OUT} = –2 mA		2.4		V
V _{OL}	Output LOW Voltage	I _{OUT} = 4 mA			0.4	V
V _{CAP}	Storage Capacitor	Between V_{CAP} pin and V_{SS} , 5V Rated		17	57	μF

DC Electrical Characteristics Over the Operating Range (V_{CC} = 2.7V to 3.6V)^[6]

Table 6. Capacitance^[7]

Parameter	Description	Test Conditions	Max.	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	7	pF
C _{OUT}	Output Capacitance	$V_{CC} = 0$ to 3.0V	7	pF

Notes:

5. Outputs shorted for no more than one second. No more than one output shorted at a time.
 6. Typical conditions for the Active Current shown on the front page of the data sheet are average values at 25°C (room temperature), and V_{CC} = 3V. Not 100% tested.
 7. These parameters are guaranteed but not tested.

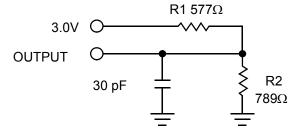


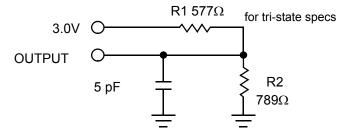
CY14B101K

Table 7. Thermal Resistance^[7]

Parameter	Description	Description Test Conditions			
Θ_{JA}	Thermal Resistance (Junction to Ambient)	Test conditions follow standard test methods and procedures for measuring thermal impedance, per EIA / JESD51.	TBD	°C/W	
Θ^{JC}	Thermal Resistance (Junction to Case)		TBD	°C/W	

AC Test Loads





AC Test Conditions

Input Pulse Levels 0V to	3V
Input Rise and Fall Times (10% - 90%) <5	ins
Input and Output Timing Reference Levels1.	5V



Table 8. AC Switching Characteristics

Parar	neters		CY14B	101K-25	CY14B	101K-35	CY14B	101K-45	Unit
Cypress Parameter			Min.	Max.	Min.	Max.	Min.	Max.	
SRAM Read	l Cycle								
t _{ACE}	t _{ACS}	Chip Enable Access Time		25		35		45	ns
t _{RC} ^[8]	t _{RC}	Read Cycle Time	25		35		45		ns
t _{AA} [9]	t _{AA}	Address Access Time		25		35		45	ns
t _{DOE}	t _{OE}	Output Enable to Data Valid		12		15		20	ns
t _{OHA} ^[9]	t _{OH}	Output Hold After Address Change	3		3		3		ns
t _{LZCE} ^[10]	t _{LZ}	Chip Enable to Output Active	3		3		3		ns
t _{HZCE} ^[10]	t _{HZ}	Chip Disable to Output Inactive		10		13		15	ns
t _{LZOE} ^[10]	t _{OLZ}	Output Enable to Output Active	0		0		0		ns
t _{HZOE} ^[10]	t _{OHZ}	Output Disable to Output Inactive	10			13		15	ns
t _{PU} ^[7]	t _{PA}	Chip Enable to Power Active	0 0			0		ns	
t _{PD} ^[7]	t _{PS}	Chip Disable to Power Standby		25		35		45	ns
SRAM Write	e Cycle		•		•			•	
t _{WC}	t _{WC}	Write Cycle Time	25		35		45		ns
t _{PWE}	t _{WP}	Write Pulse Width	20		25		30		ns
t _{SCE}	t _{CW}	Chip Enable To End of Write	20		25		30		ns
t _{SD}	t _{DW}	Data Set-Up to End of Write	10		12		15		ns
t _{HD}	t _{DH}	Data Hold After End of Write	0 0 0		0		ns		
t _{AW}	t _{AW}	Address Set-Up to End of Write	20 25			30		ns	
t _{SA}	t _{AS}	Address Set-Up to Start of Write	0		0		0		ns
t _{HA}	t _{WR}	Address Hold After End of Write	0 0			0		ns	
t _{HZWE} ^[10,11]	t _{WZ}	Write Enable to Output Disable		10		13		15	ns
t _{LZWE} ^[10]	t _{OW}	Output Active after End of Write	3		3		3		ns

 Notes:

 8. WE must be HIGH during SRAM Read Cycles.

 9. Device is continuously selected with CE and OE both Low.

 10. Measured ±200mV from steady state output voltage.

 11. If WE is Low when CE goes Low, the outputs remain in the High Impedance State



Table 9. AutoStore/Power-up RECALL

		CY14	3101K	
Parameters	Description			Units
t _{HRECALL} ^[12]	Power-Up RECALL Duration		20	ms
STORE ^[13]	STORE Cycle Duration		12.5	ms
V _{SWITCH}	Low Voltage Trigger Level	2.55	2.65	V
t _{VCCRISE}	VCC Rise Time	150		μS

Table 10.Software Controlled STORE/RECALL Cycle^[14,15]

		CY14B101K-25 CY14		CY14B1	01K-35	CY14E	CY14B101K-45	
Parameters	Description	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{RC}	STORE/RECALL Initiation Cycle Time	25		35		45		ns
t _{AS}	Address Set-Up Time	0		0		0		ns
t _{CW}	Clock Pulse Width	20		25		30		ns
t _{GLAX}	Address Hold Time	20		20		20		ns
t _{RECALL}	RECALL Duration		40		40		40	μS

Table 11.Hardware STORE Cycle

		CY14		
Parameters	Description	Min	Max	Units
t _{DELAY} ^[16]	Time allowed to complete SRAM Cycle	1		μS
t _{HLHX}	Hardware STORE Pulse Width	15		ns
t _{HLBL}	Hardware STORE Low to STORE Busy		300	ns

Switching Waveforms

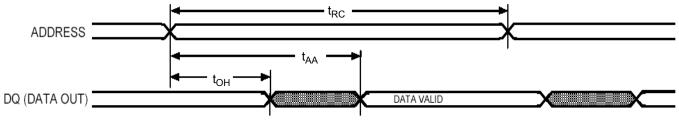


Figure 5. SRAM Read Cycle #1: Address Controlled^[8,9,17]

Notes:

 Notes:

 12. t_{HRECALL} starts from the time V_{CC} rises above V_{SWITCH}.

 13. If an SRAM Write has not taken place since the last nonvolatile cycle, no STORE will take place.

 14. The software sequence is clocked with CE controlled or OE controlled READs.

 15. The six consecutive addresses must be read in the order listed in the Mode Selection table. WE must be HIGH during all six consecutive cycles.

 16. Read and Write cycles in progress before HSB are given this amount of time to complete.

 17. HSB must remain HIGH during READ and WRITE cycles.



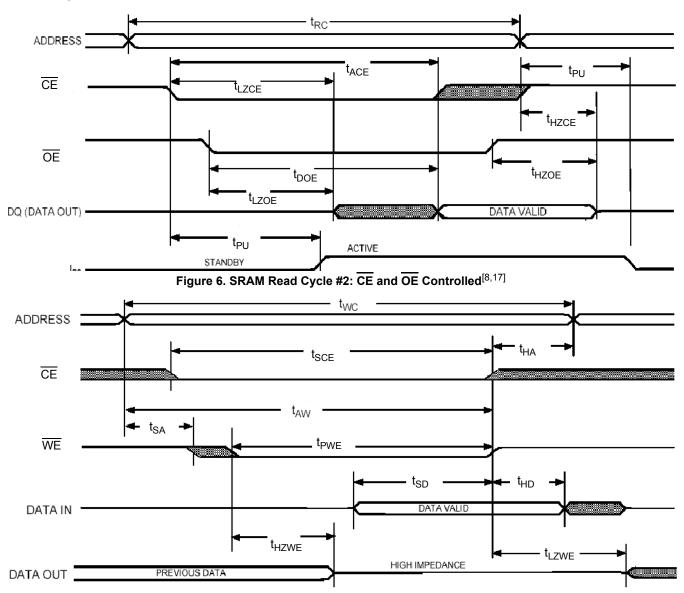
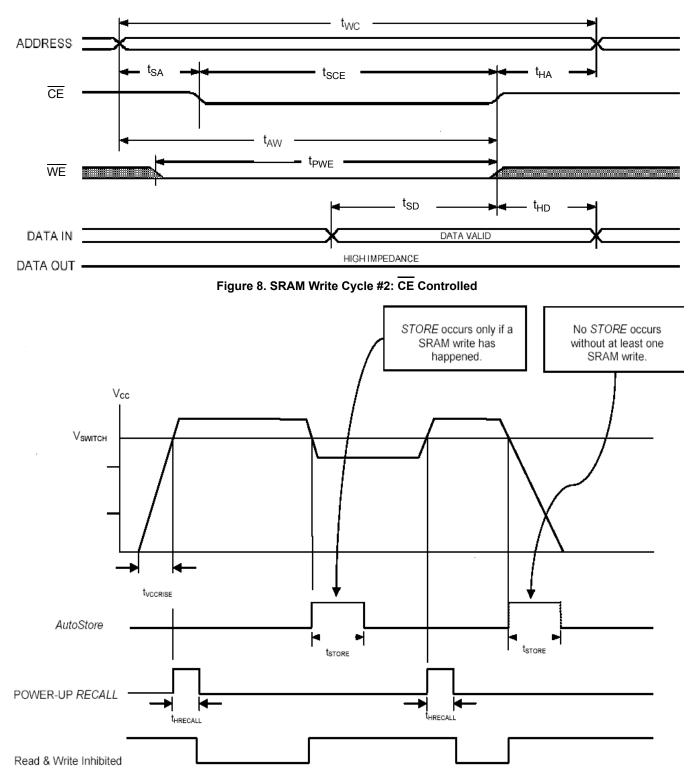


Figure 7. SRAM Write Cycle #1: WE Controlled^[17,18]

Note: 18. \overline{CE} or \overline{WE} must be > V_{IH} during address transitions.

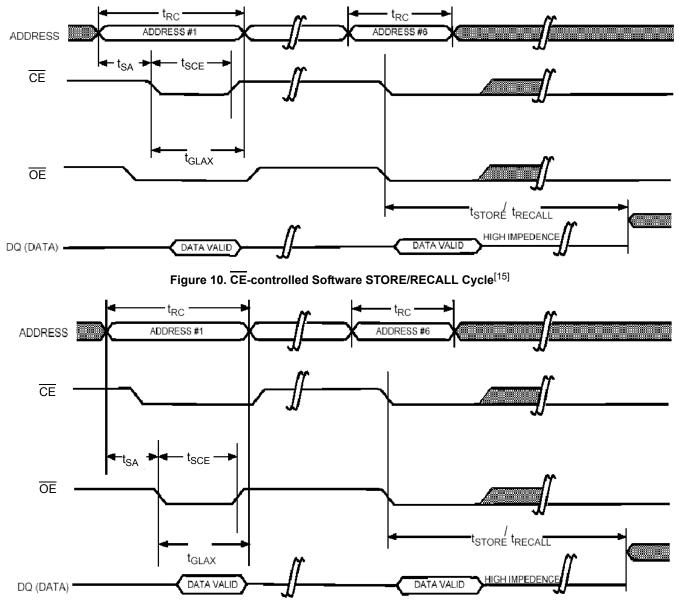






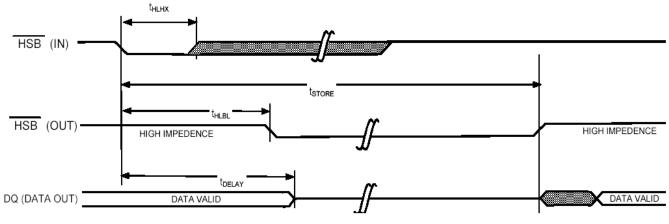


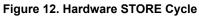






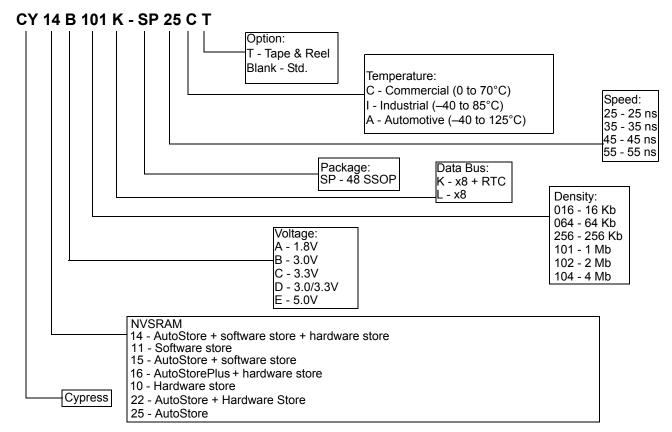








PART NUMBERING NOMENCLATURE



Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B101K-SP25CT	51-85061	48-pin SSOP Pb-Free	Commercial
	CY14B101K-SP25IT	51-85061	48-pin SSOP Pb-Free	Industrial
	CY14B101K-SP25I	51-85061	48-pin SSOP Pb-Free	
45	CY14B101K-SP45CT	51-85061	48-pin SSOP Pb-Free	Commercial
	CY14B101K-SP45IT	51-85061	48-pin SSOP Pb-Free	Industrial
	CY14B101K-SP45I	51-85061	48-pin SSOP Pb-Free	

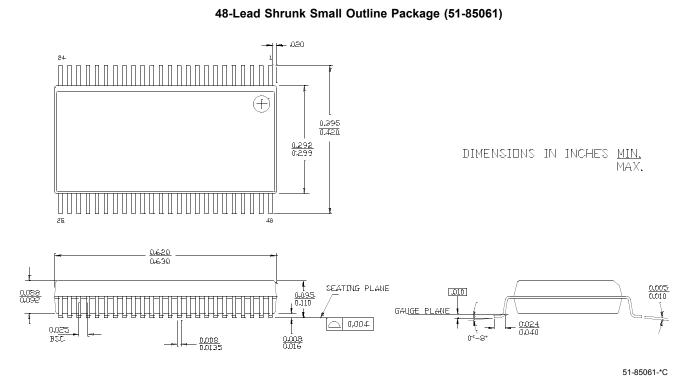
Shaded areas contain advance information. Please contact your local Cypress sales representative for availability of these parts.





CY14B101K

Package Diagrams



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Document History Page

Document Title: CY14B101K 1-Mbit (128K x 8) nvSRAM With Real-Time Clock Document Number: 001-06401							
REV.	ECN NO.	lssue Date	Orig. of Change	Description of Change			
**	425138	See ECN	TUP	New Data Sheet			
*A	437321	See ECN	TUP	Show Data Sheet on external Web			